

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/027,488	NEEDHAM ET AL.
	<b>Examiner</b> Thien D. Tran	<b>Art Unit</b> 2616

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	331	4/26/2006	TT
455	442, 519	4/6/2006	TT